

On track for discovery of sub-GeV dark matter with liquid xenon TPCs

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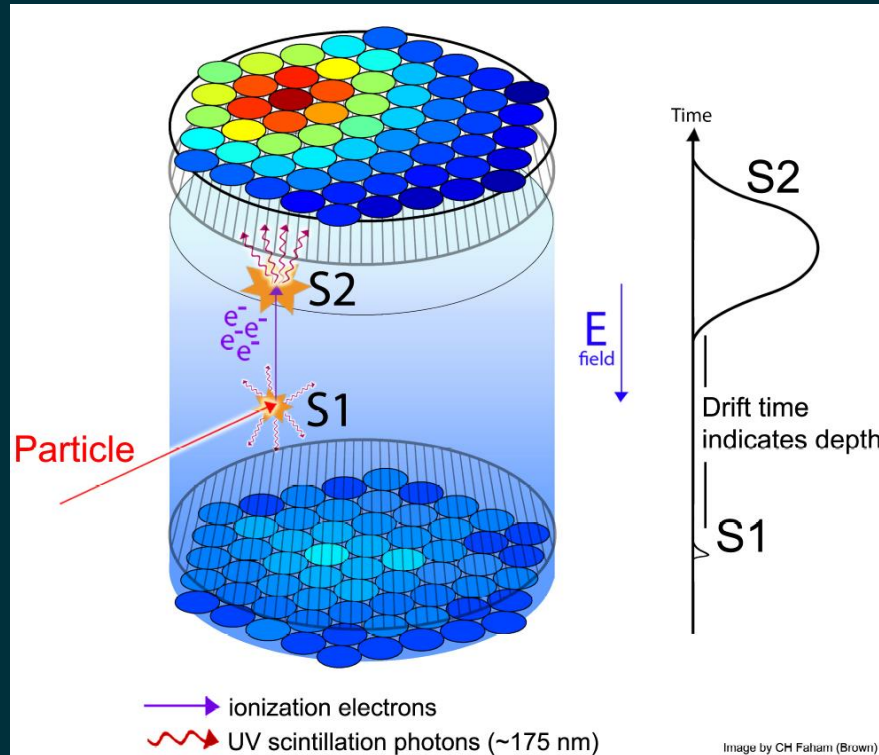
TeVPA Chicago 2024

8/26/2024

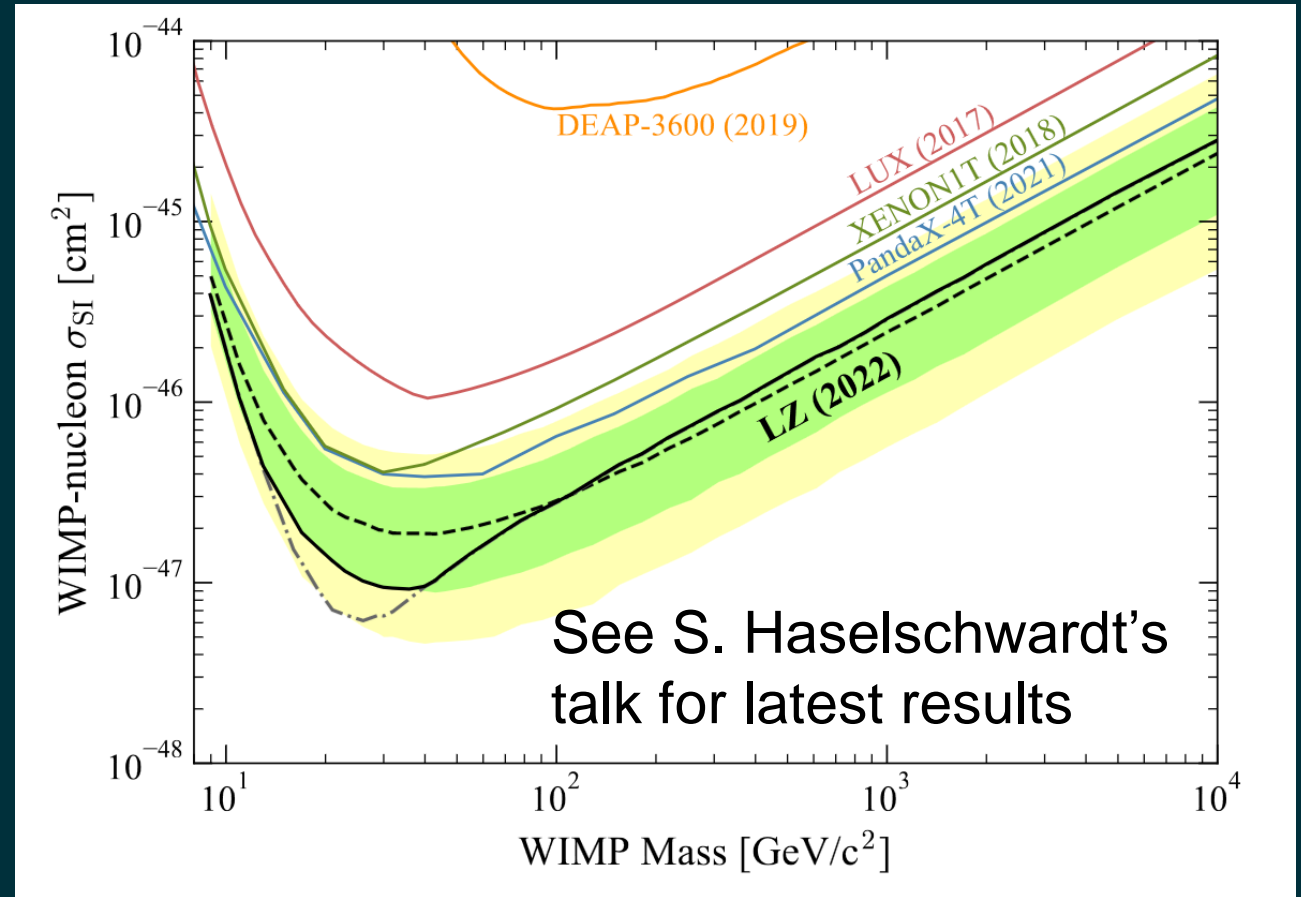


Xenon TPCs – leading the way in WIMP sensitivity

LZ: 2207.03764

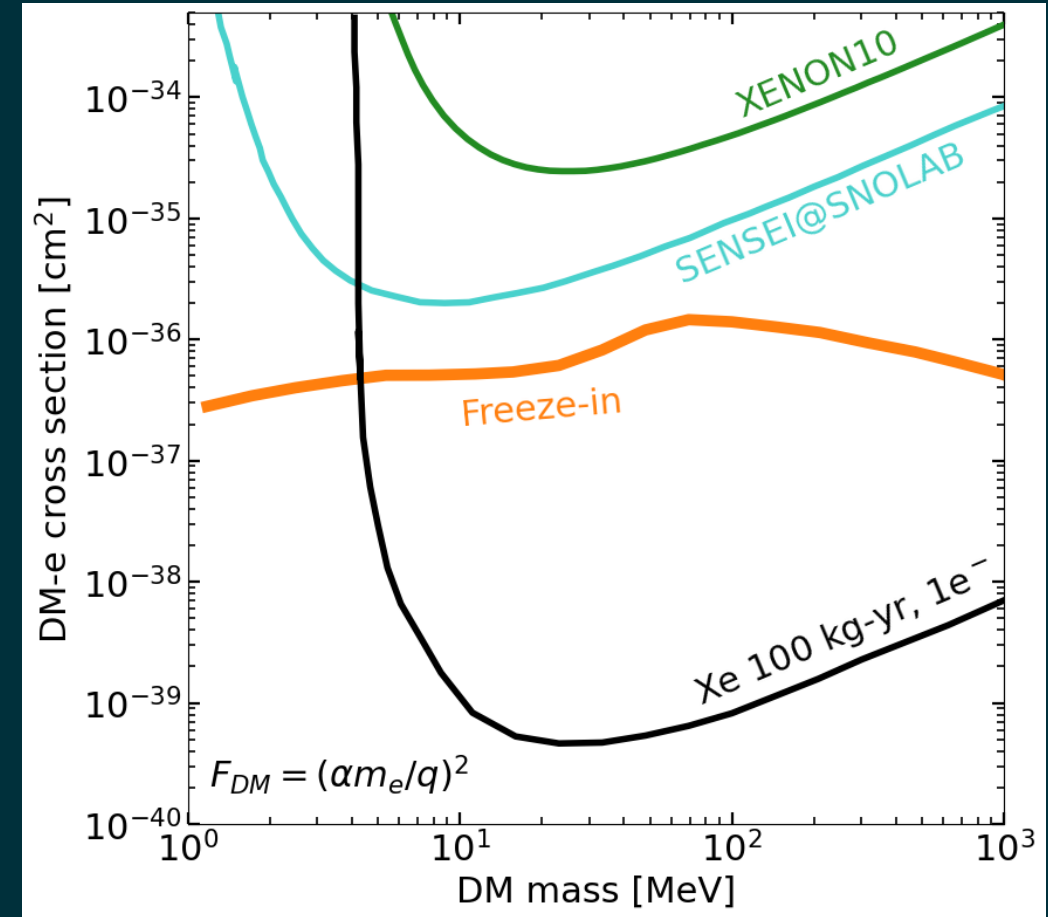
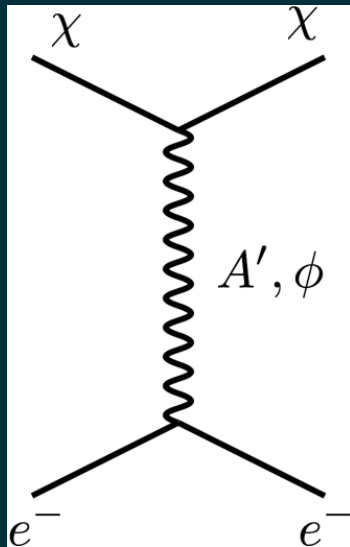


S1: light signal
S2: charge signal



Low-mass dark matter with charge-only signal

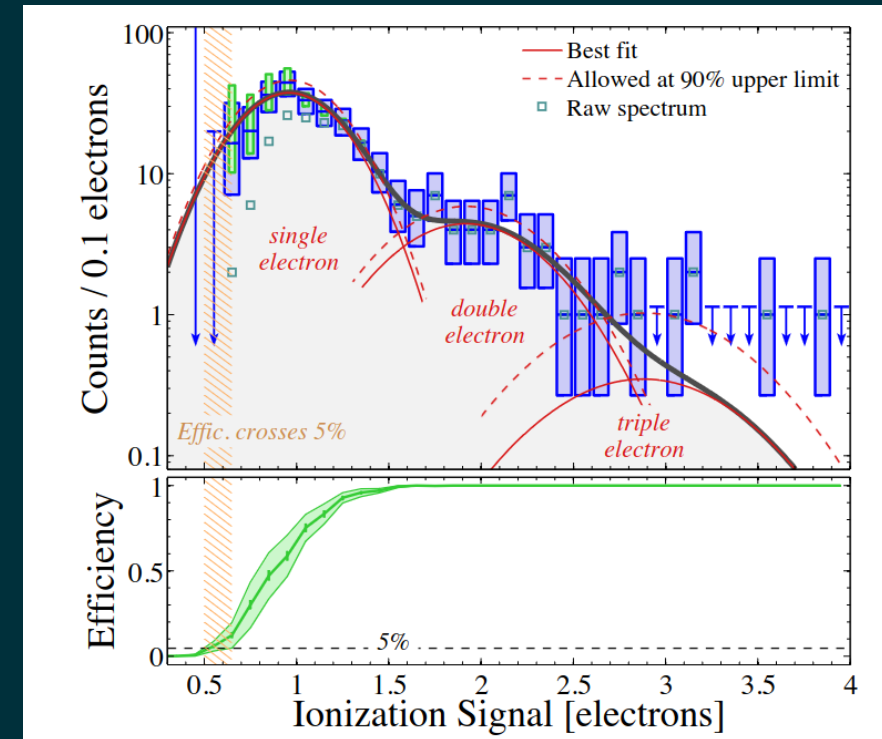
- Min. low-energy threshold, $E_g = 9.2$ eV
- Attractive for DM-electron scatter searches
 - E.g., hidden sector models



Dominant background – delayed electron emission

XENON10 data: 1206.2644
See also 1104.3088

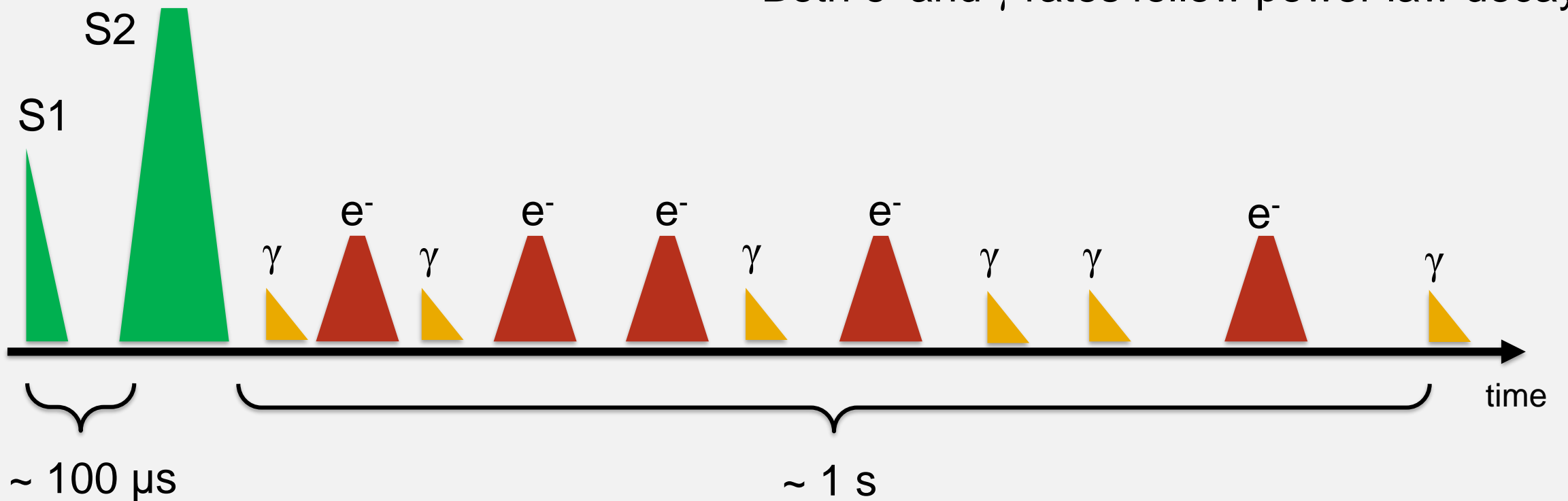
- Delayed electron emission – “electron trains”
 - Radioactive backgrounds (Rn) subdominant for few-electron signals
- Remove detector backgrounds, the next step is either dark matter or the neutrino fog*
 - The origin of electron trains has remained elusive



Events are due to electron trains

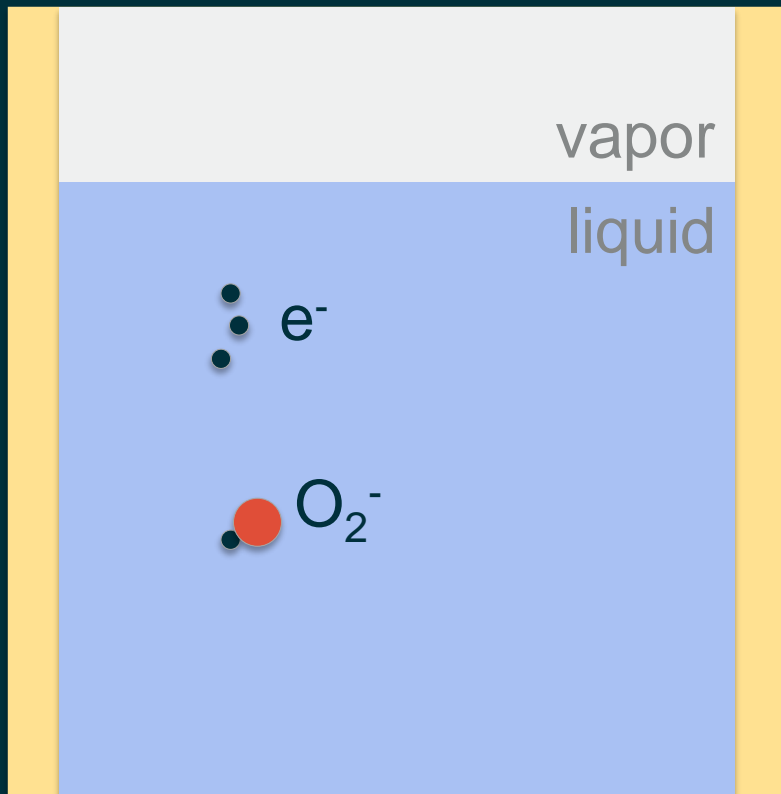
Delayed emission – electron and photon “trains”

Both e^- and γ rates follow power law decay

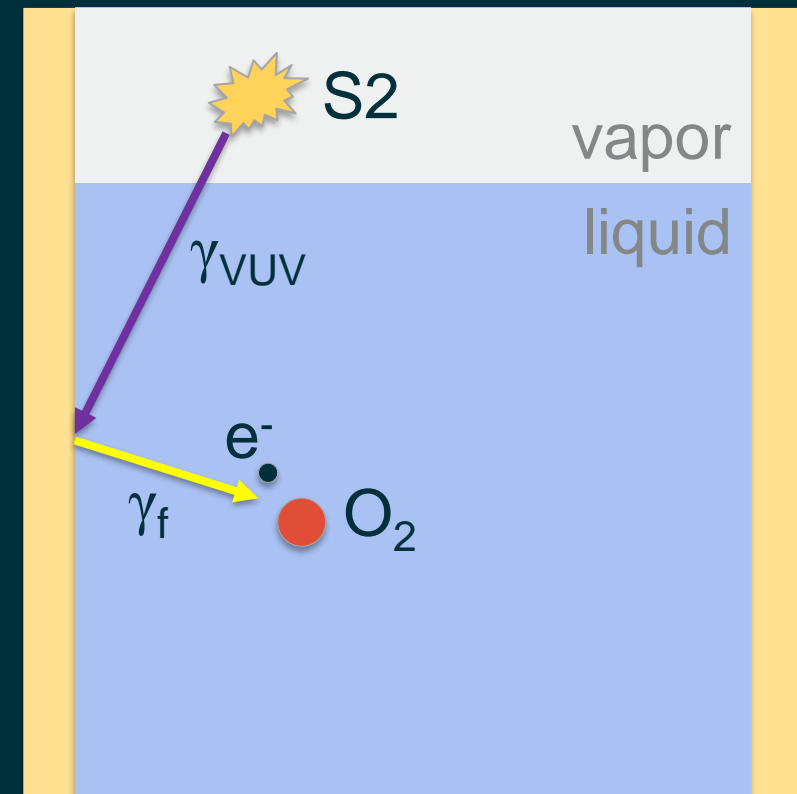


Conclusion first: what causes electron trains?

1. Drifting electrons are trapped on impurities in xenon



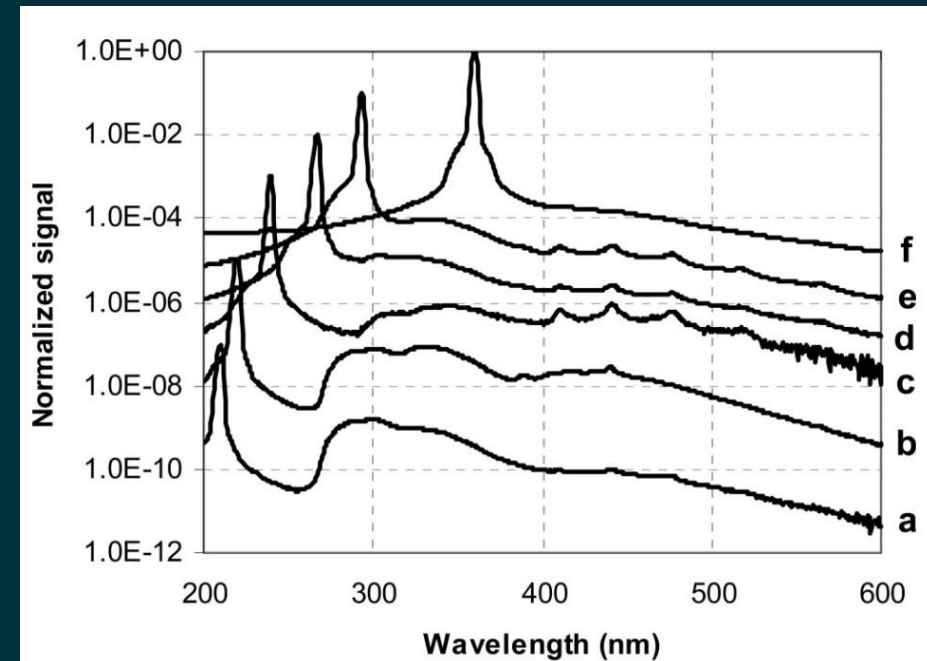
2. Trapped electrons are released via photoionization from fluorescence



What causes photon trains?

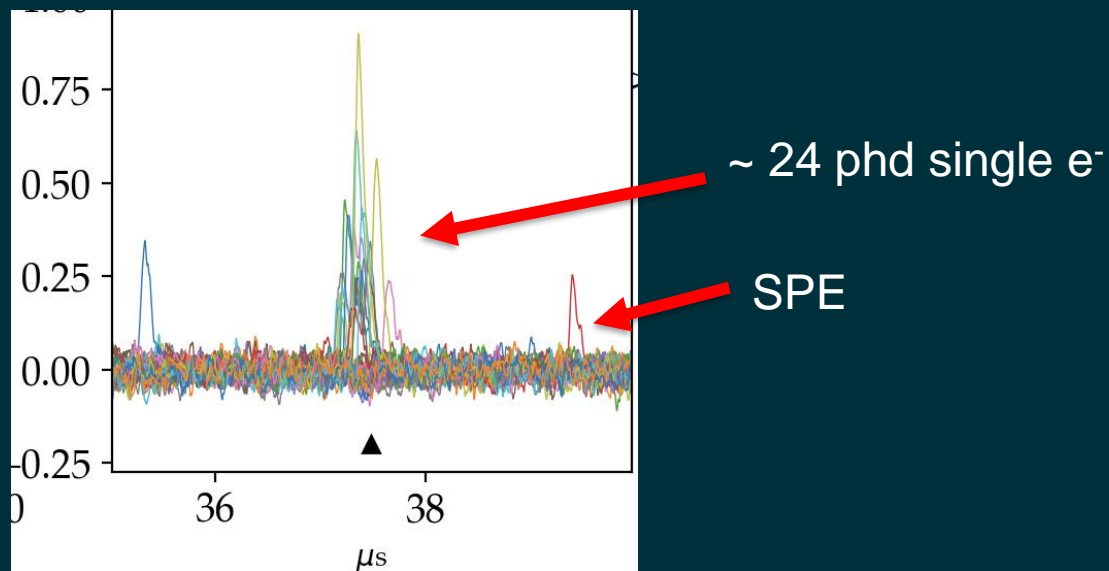
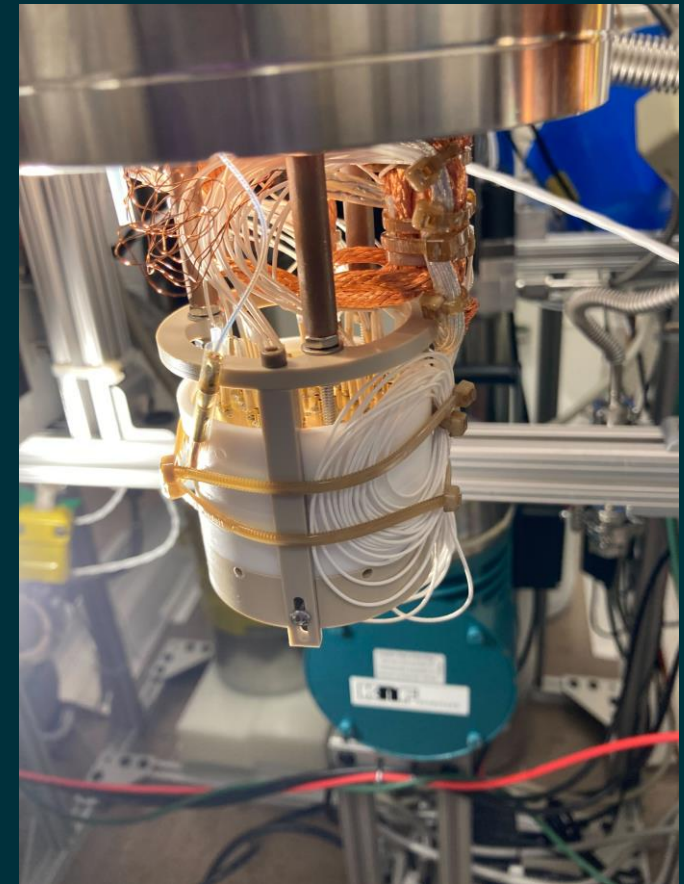
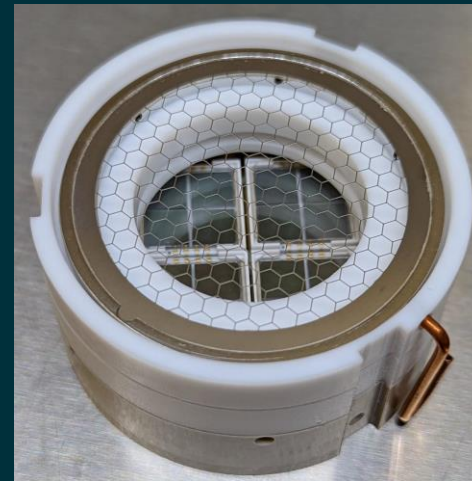
- Impurities in detector materials fluoresce from Xe VUV light
- PTFE is likely dominant source in Xe TPCs
- All dielectrics are suspect (PEEK, acrylic, ...)

Shaw et. al. (2007)
Fluorescence spectra of PTFE at
varying UV energy excitations



Investigations with xenon TPC at LBNL

- ~ 700 g dual-phase xenon TPC
- 32 SiPM channels
- Typical single electron ~ 20-30 phd

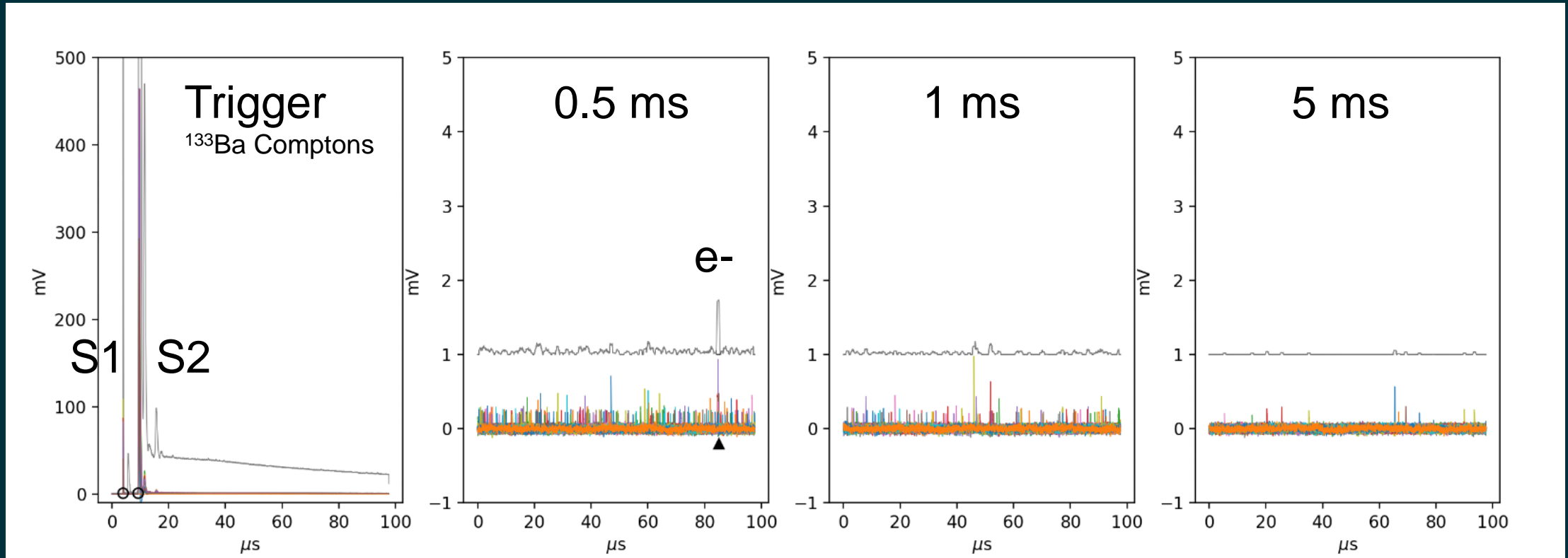


More work from this test stand:

- Solid Xe TPC (crystalize): 2312.15082, 2201.05740
- H/He-doping Xe (HydroX): 2308.02430
- SiPM G3 R&D: 2309.07913

Delayed signal in liquid/vapor xenon TPC

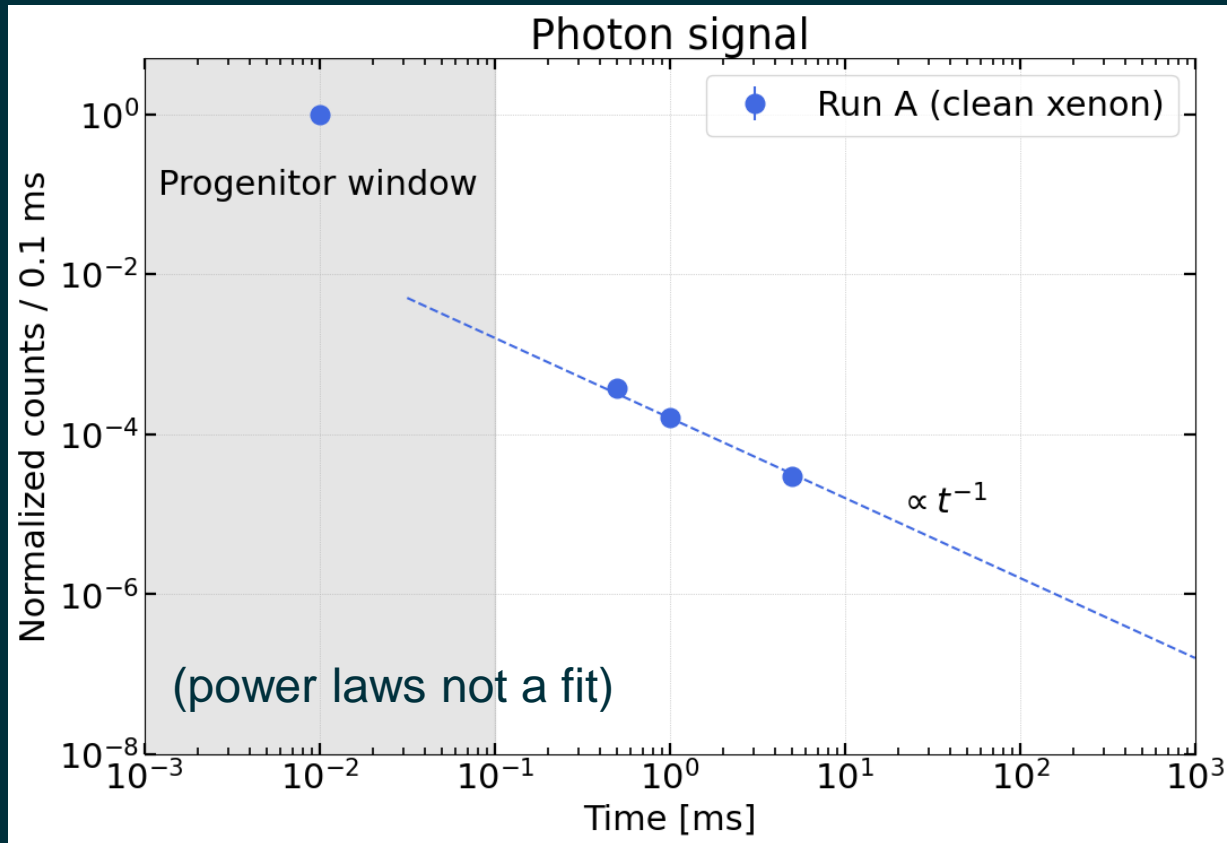
Observe delayed electrons and photons



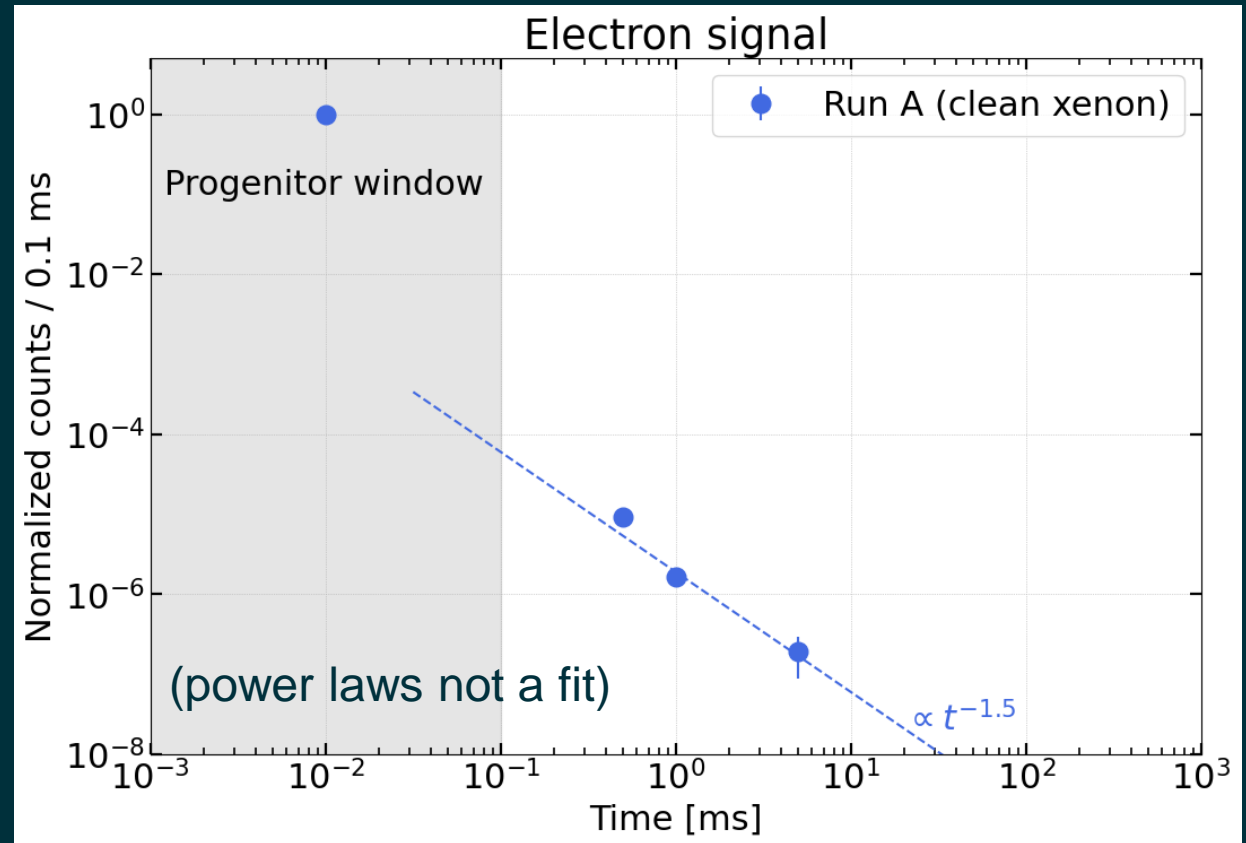
Using “cascade trigger” to sample delayed times

Nominal delayed emission rates

Delayed photon emission

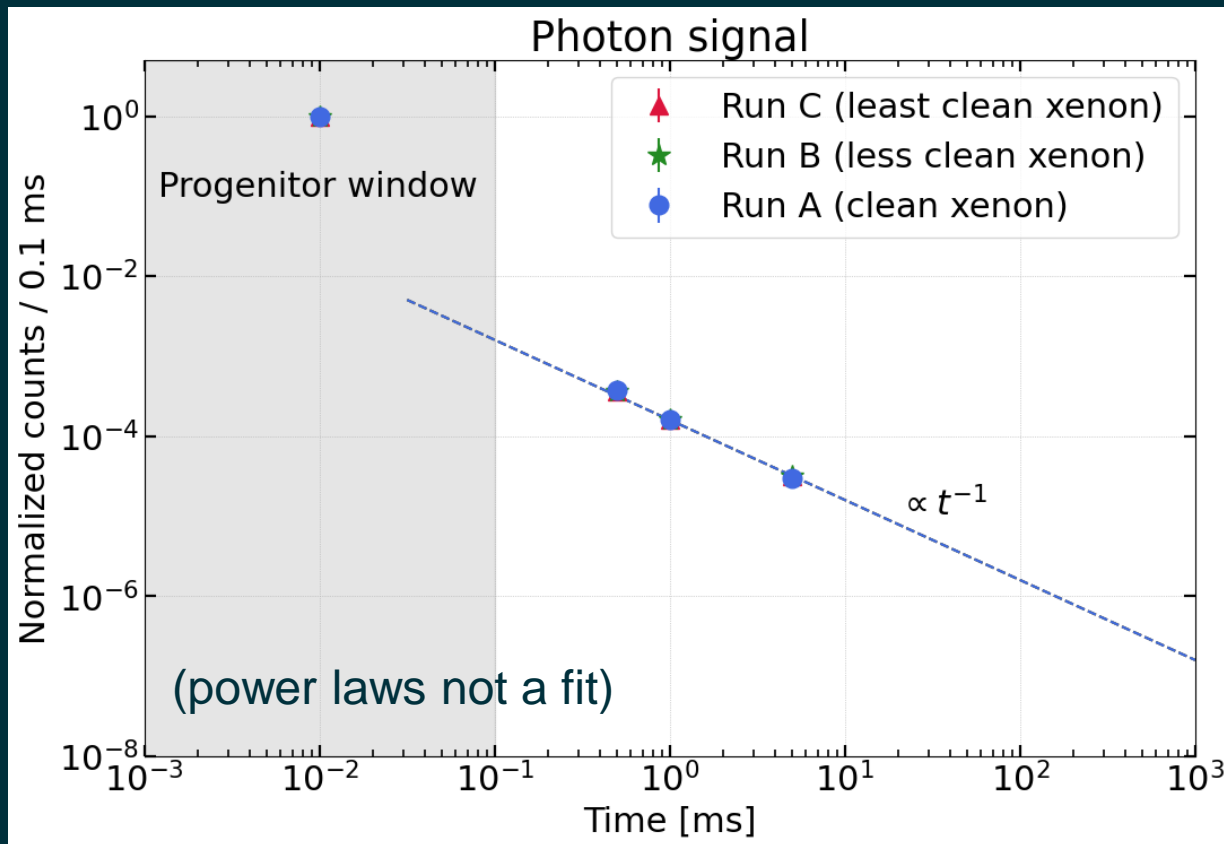


Delayed electron emission

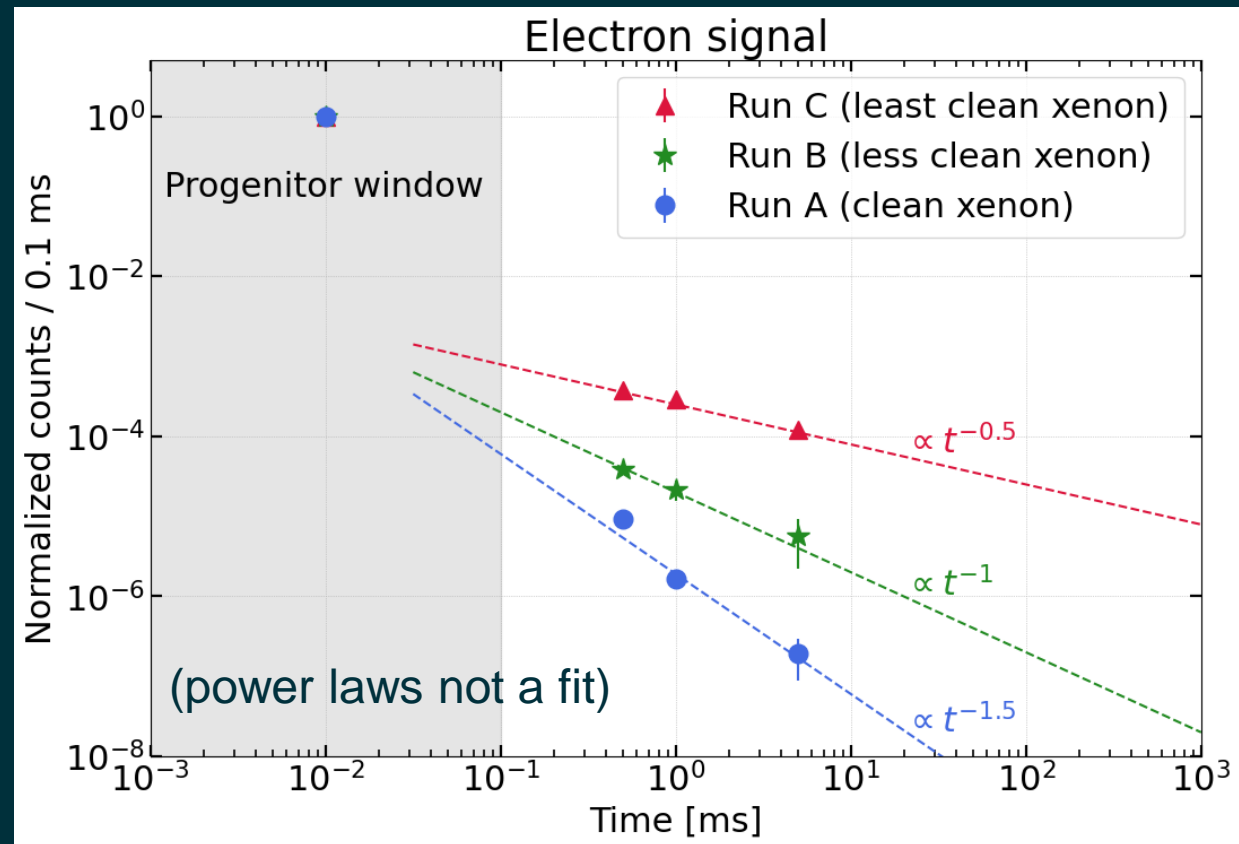


Increase impurities in xenon \rightarrow increase electron trains

Photon trains unaffected by xenon impurities



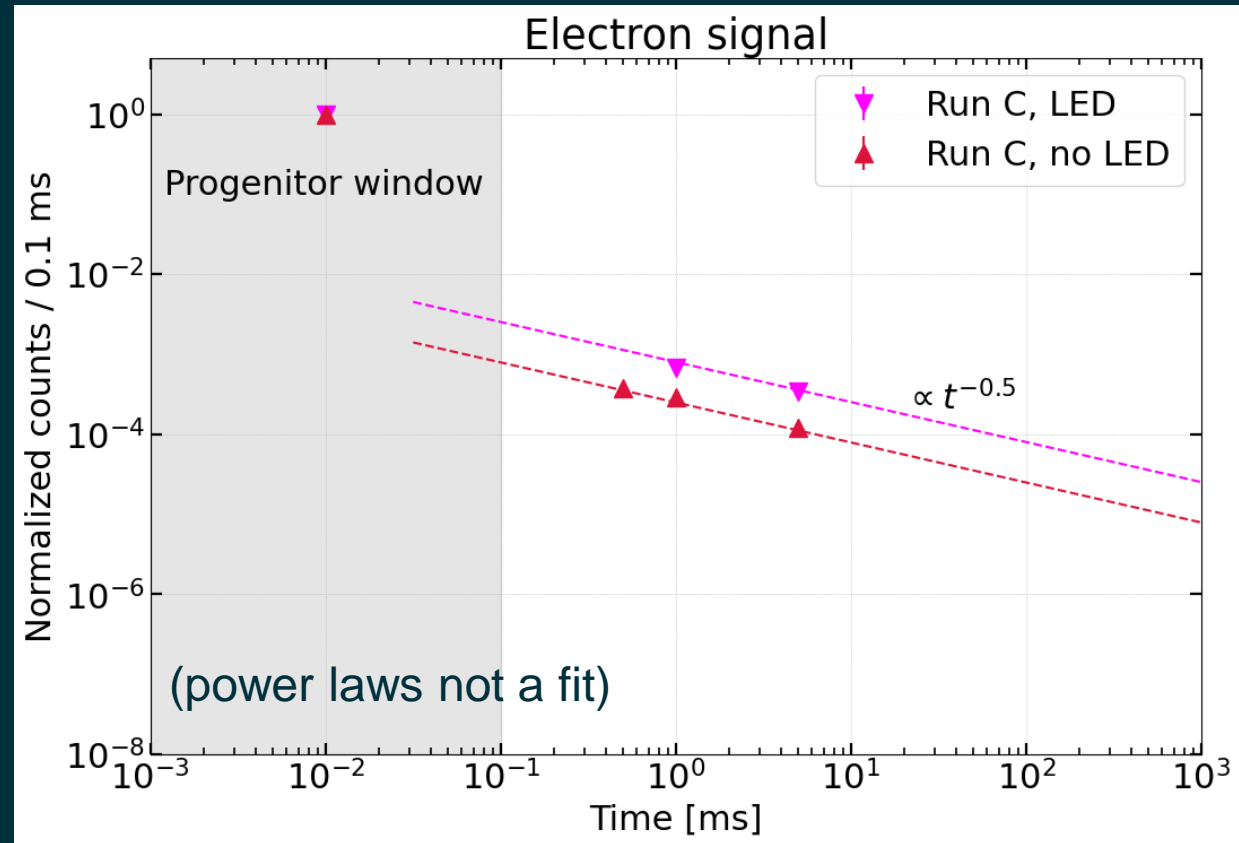
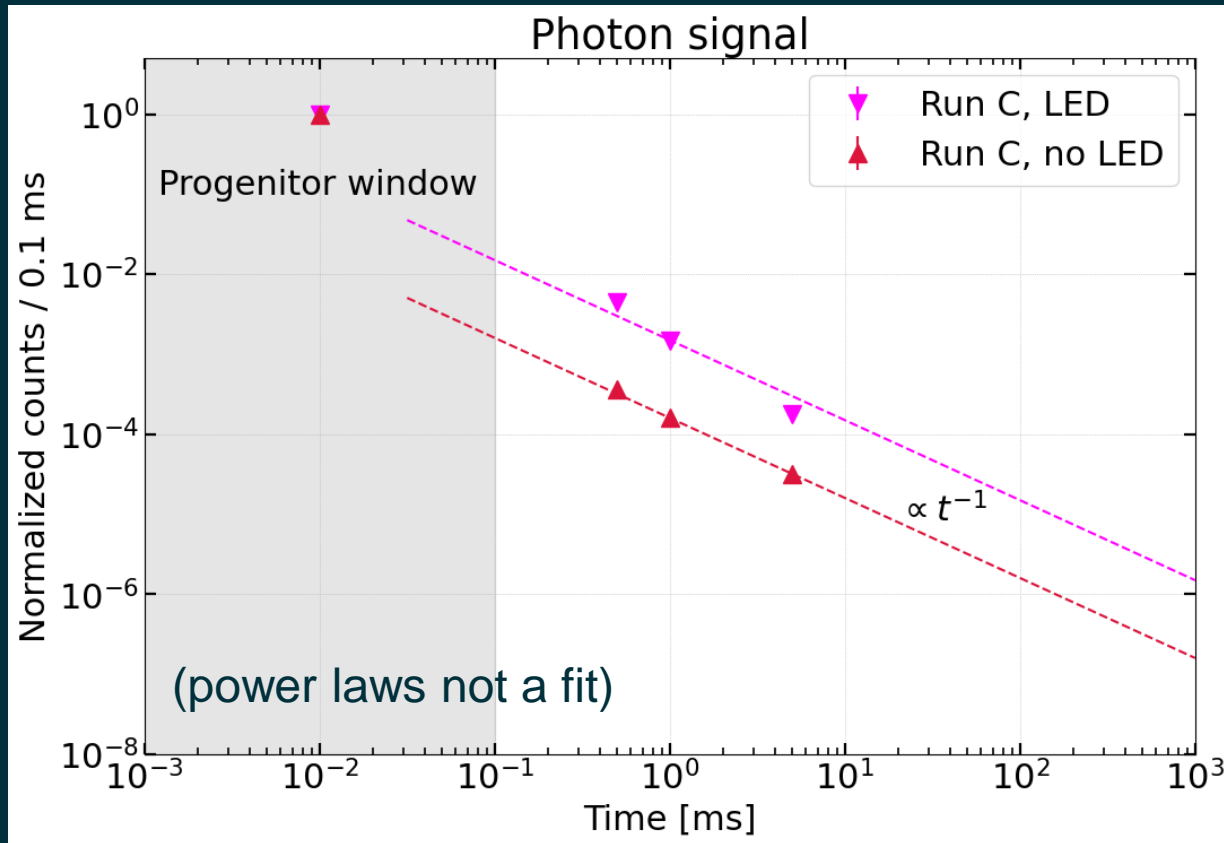
Increase in electron trains, agreeing with prior work



Adding 235 nm LED flash after particle scatter

Photon emission $\sim x5$ increase

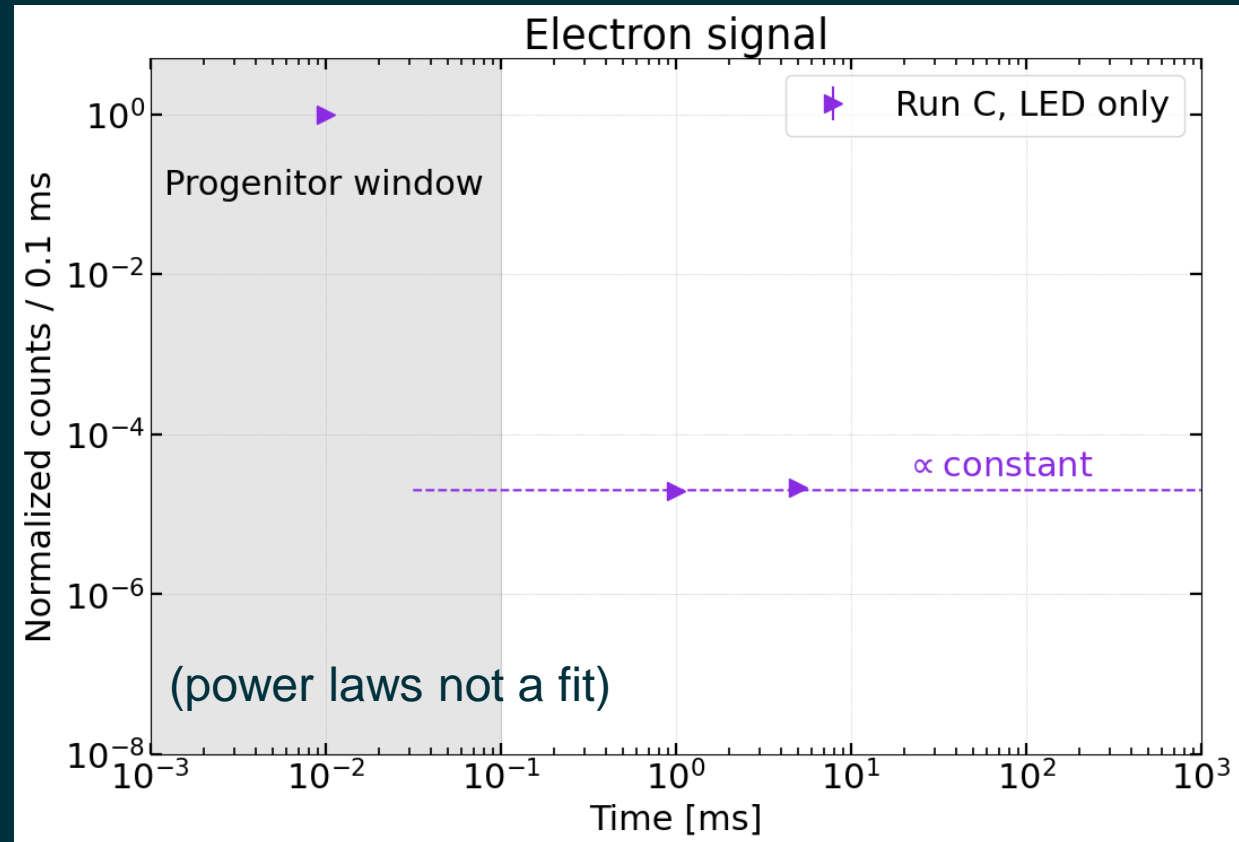
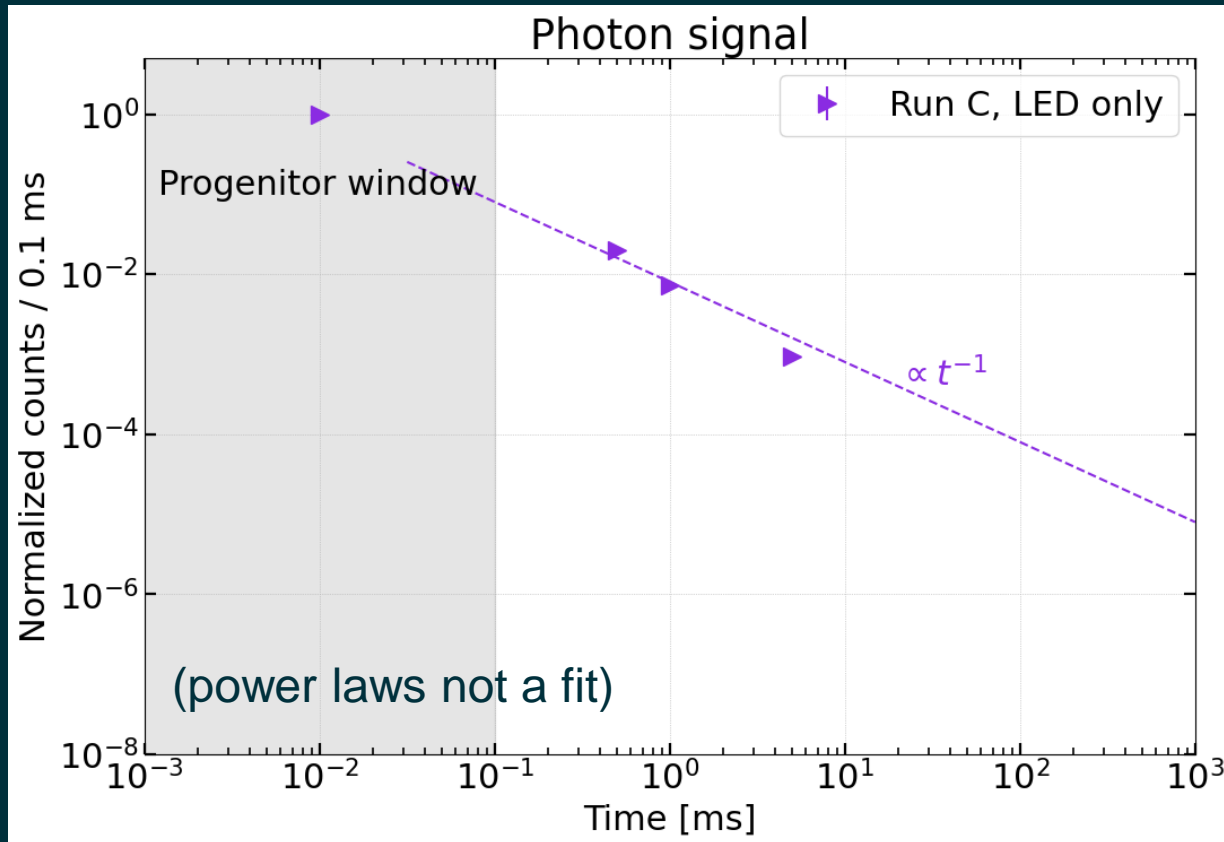
Electron emission $\sim x3$ increase!



LED-only → no electron trains

Still see photon trains!
Indicative of UV induced fluorescence

Electron rate constant
→ background e- noise



Photon trains cause electron trains

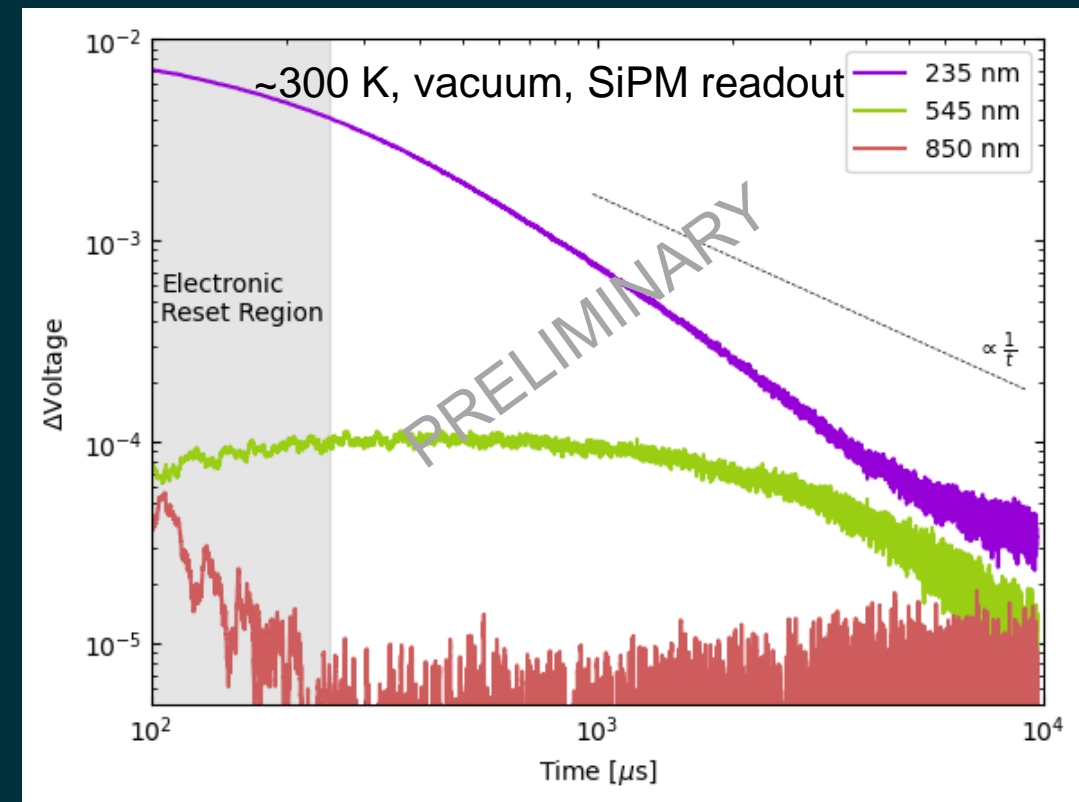
given impurities in xenon bulk

Characterizing fluorescence (photons trains) at LBNL

- Small vacuum/Xe test chamber to measure delayed photon emission
 - PTFE, PEEK, acrylic, ...
- Identify the main source(s) of photon trains

Difference between PTFE and control →

Work with undergrad Leah Douglas



Implications for GeV WIMP dark matter searches

- Electron/photon trains are major contributor to accidental coincidences
 - Cause significant cut to detector livetime
- Accidentals rate has increased with size of detector
 - Reducing delayed emission necessary for XLZD/G3

Summary

- Dual-phase xenon TPCs have sensitivity to sub-GeV dark matter
 - Currently hindered by delayed electron emission
- Delayed electron emission caused by delayed photon emission
 - Given impurities in the bulk xenon
- Work ongoing at LBNL to characterize delayed electron and photon emission

